PAUL SCHERRER INSTITUT

9th QCA Final Presentation Day – 27th & 28th of January 2009.

10:00-10:10 Welcome and Overview (Final Agenda)

Paul Scherrer Institut, CH – Martin Jermann
European Space Agency/ESTEC, NL - Reno Harboe Sørensen
Paul Scherrer Institut, CH – Wojtek Hajdas

10:10-10:40 Total Dose and Single Event Effects in Commercial PWM's and Gate Drivers.
Radiation Evaluation of UC2843 and UC2845 from STMicroelectronics.

RUAG Aerospace Sweden AB, Sweden – Stanley Mattsson

10:40-10:55 Single Event Effect Radiation Testing of LTC2449 24-Bit ADC and LTC6241 OpAmp from Linear Technology.

DLR, Berlin, Germany – Joerg Knollenberg

10:55-11:25 Optocoupler Study – Preliminary Analysis & Results Following Proton Testing.

EADS Astrium, France – Daniel Peyre/Christian Binois

11:25-11:40 Study of Radiation Effects in MEMS.

EADS Astrium, France – Oudea Coumar

11:40-11:55 Total Dose Test of Low Power PWM UCC1801 and UCC1806.
RUAG Aerospace Sweden AB, Sweden – Sture Larsson

11:55-12:15 Update on Single Event Effects in GaAs MESFETs
ESA/ESTEC, The Netherlands – Fredrik Sturesson

12:15-12:30 Experimental Validation of Fault Injection Analysis with the FLIPPER Tool.
INAF/IASF, Milano, Italy – Monica Alderighi

12:30-14:00 Lunch Break

14:00-14:25 SEE and TID Radiation Test Results on ST Circuits in 65 nm CMOS Technologies.
STMicroelectronics, Crolles, France – Philippe Roche

14:25-14:45 Heavy Ion Energy and Tilting Effects in FLASH Memories
University of Padova, Italy –
Giorgio Cellere/Alessandro Paccagnella

14:45-15:00 Heavy Ion LET in Silicon.

University of Jyväskylä, Finland –
Arto Javanainen/Ari Virtanen

15:00-15:15 Technology Demonstration Module for PROBA-II.

Verhaert Space, Belgium – Koen Puimege/Nico Fleurinck

15:15-15:35 Coffee Break

15:35-15:50 New RADFETs for Space Applications

Tyndall National Institute, Ireland – Aleksandar Jaksic

15:50-16:10 Radiation Evaluation of Samsung 8 Gbit FLASH Memories for Space Applications.

IDA, Braunschweig, Germany –Hagen Schmidt/Fritz Gliem

16:10-16:30 SEL Characterisation of SRAMs for the TDM Latch-up Experiment.

HIREX Engineering, France –
Francois-Xavier Guerre/Frederic Lochon

16:30-16:50 Reverse Engineering of SRAMs Selected for the TDM
Tyndall National Institute, Ireland –
Richard Fitzgerald/Ted O'Shea

16:50-17:10 Laser Single Event Effects Studies Phase IV – Latch-up Investigations of SRAMs Selected for the TDM.
MBDA UK Ltd, United Kingdom – Andrew Chugg

17:10-17:40 News from the European Component Irradiation Facilities, PIF, HIF/LIF, RADEF & ECF.

PIF – *Wojtek Hajdas*
HIF – *Guy Berger*
RADEF – *Ari Virtanen*
ECF – *Bob Nickson*

17:40 End of Day 1 Presentations

18:00 Start of Social Programme – Schloss Böttstein